Application/Control No. Applicant(s)/Patent Under Reexamination 10/621,677 CHEN ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 TAN X. DINH 2627 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification MM-YYYY Country Code-Number-Kind Code US-Α US-В US-С US- · D US-Ε US-F US-G US-Н US-J US-US-Κ

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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